Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/721,673	QIN ET AL.	
Examiner	Art Unit	
Phallaka Kik	2825	

	SEAR	CHED	
Class	Subclass	Date	Examiner
716	2,3,5,6,13, 14,7	7/21/2006	РК
Above	New	8/5/2006	PK
Above	New	8/8/2006	PK

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
BRS (EAST)USPAT, USPGPUB Class/Sub searched: 716/1-18; 703/2,14-16 (see attached)	7/21/2006	PK
EPO, JPO, IBM TDB, Derwent (see attached)	7/21/2006	PK
IEE/IEEE Xplore (see attached)	7/21/2006	PK
All above new search (see attached)	8/5/2006	PK
All above new search (see attached)	8/8/2006	PK